
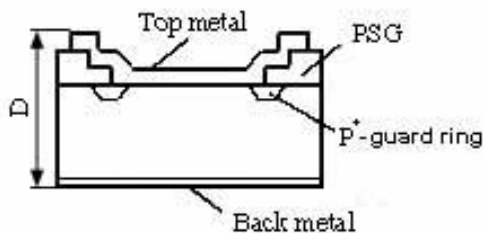
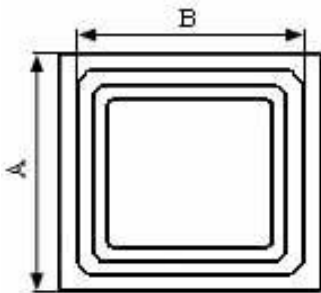


| | | 10A/40V. Die Size-106mil. | | |
|--|-------------|---|--------------------|------------------------|
| | |  | | |
| Electrical Characteristics | Symbol | Unit | Spec. limit | Die Sort |
| Breakdown Voltage @ $I_R=10\text{mA}$ | V_{BR} | V | 40 | 45 |
| Average Rectified Forward Current | $I_{F(AV)}$ | A | 10,0 | - |
| DC Forward Voltage @ 25°C, $I_F=10,0\text{A}$ | V_F | V | 0,50 | 0,48 |
| Maximum Reverse Current @ 25°C, $V_R=45\text{V}$ @ 25°C, $V_R=40\text{V}$ @ 125°C, $V_R=40\text{V}$ | I_R | mA | - 0,150 55,0 | 0,150 0,100 50,0 |
| Peak Forward Surge Current 8,3ms single half sine-wave superimposed on rated load (JEDEC METHOD) | I_{FSM} | A | 180 | - |
| Peak Repetitive Reverse Surge Current @ 2,0µs, f=1kHz., $T_J<150^\circ\text{C}$. | I_{RRM} | A | 3,5 | |
| Electrostatic Discharge Voltage. JEDEC Method. ESD HBM. Contact. | ESD | kV | ±8 (contact) | |
| Voltage Rate of Change | dV/dt | V/µS | 10.000 | |
| Operating Junction Temperature | T_J | °C | 150 | |



| DIM | ITEM | µm |
|----------------------------------|---------------------|--------------|
| A _x A _y | Wafer Form Die Size | 2700 2700 |
| B _x B _y | Top Metal Size | 2560 2560 |
| D | Thickness | 300max. |
| Scribe line Width | | 80 |

Top metal:

- a) Al – for Wire Bonding;
 - b) Al-Ni-Ag – for Soldering.
- Backside metal: Ti-Ni-Ag.